

RoHS

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FREE

# AON3816-VB Datasheet Dual N-Channel 20 V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω)	I <sub>D</sub> (A)	Q <sub>g</sub> (TYP.)			
	0.0170 at V <sub>GS</sub> = 4.5 V	20				
20	0.0240 at V <sub>GS</sub> = 2.5 V	17	12 nC			
	0.0490 at V <sub>GS</sub> = 1.8 V	10				

3.30 mm

DFN 3.3x3.3

Bottom View

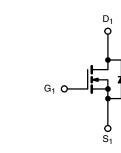
. 3.30 mm

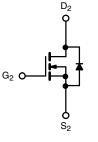
### FEATURES

• TrenchFET® power MOSFET

#### **APPLICATIONS**

- DC/DC
- Notebook system power
- POL





N-Channel MOSFET

N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATING</b>	<b>S</b> (T <sub>A</sub> = 25 °C, ι	Inless otherwis	se noted)		
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V <sub>DS</sub>	20	V	
Gate-Source Voltage		V <sub>GS</sub>	± 8	V	
	T <sub>C</sub> = 25 °C		20		
Continuous Drain Current (T. 150 °C)	T <sub>C</sub> = 70 °C	1 , [	15.8		
Continuous Drain Current ( $T_J = 150 \ ^\circ C$ )	T <sub>A</sub> = 25 °C		<b>8</b> a, b		
	T <sub>A</sub> = 70 °C	1	6.5 <sup>a, b</sup>	•	
Pulsed Drain Current		I <sub>DM</sub>	40	A	
	T <sub>C</sub> = 25 °C		15		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.2 <sup>a, b</sup>		
Single Pulse Avalanche Current	ne Current		15		
Single Pulse Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	11	mJ	
	T <sub>C</sub> = 25 °C		20		
Manimum Danna Diasis atisa	T <sub>C</sub> = 70 °C		12.8	14/	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	2.5 <sup>a, b</sup>	W	
	T <sub>A</sub> = 70 °C	1 –	1.6 <sup>a, b</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150		
Soldering Recommendations (Peak Temperature) <sup>c, d</sup>		1 Č	260		

THERMAL RESISTANCE RATIN	GS				
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT
Maximum Junction-to-Ambient	$t \le 10 s$	R <sub>thJA</sub>	38	48	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	4.3	5.4	C/W

Notes

a. Package limited,  $T_C = 25 \text{ °C}$ .

b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under Steady State conditions is 110 °C/W.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static	11		1		1	_
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA	20	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L 050 A	-	22	-	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = 250 μA	-	-3	-	mv/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$	0.4	-	1	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 8 V$	-	-	± 100	nA
		$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$	-	-	10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	20	-	-	Α
		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	-	0.0170	-	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 2.5 \text{ V}, \text{ I}_{D} = 9 \text{ A}$	-	0.0240	-	mV/°C
		$V_{GS} = 1.8 \text{ V}, \text{ I}_{D} = 8.2 \text{ A}$	-	0.0490	-	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	-	47	-	S
Dynamic <sup>b</sup>						•
Input Capacitance	C <sub>iss</sub>		-	1120	-	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	-	180	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	80	-	
		$V_{DS} = 15 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 10 \text{ A}$	-	21	32	
Total Gate Charge	Qg		-	12	18	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$	-	2	-	nC
Gate-Drain Charge	Q <sub>gd</sub>		-	1.3	-	
Gate Resistance	R <sub>q</sub>	f = 1 MHz	-	1.8	3.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>		-	10	15	
Rise Time	t <sub>r</sub>	$V_{DD} = 10 \text{ V}$ , $B_1 = 1.25 \Omega$	-	10	15	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 8 \text{ A}, V_{\text{GEN}} = 4.5 \text{ V}, R_g = 1 \Omega$	-	35	55	
Fall Time	t <sub>f</sub>		-	10	15	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD}$ = 10 V, R <sub>L</sub> = 1.25 Ω $I_D \cong$ 8 A, V <sub>GEN</sub> = 4.5 V, R <sub>g</sub> = 1 Ω $V_{DD}$ = 10 V, R <sub>L</sub> = 1.25 Ω		10	15	ns
Rise Time	t <sub>r</sub>	$V_{DD} = 10 \text{ V}$ , $B_1 = 1.25 \Omega$	-	10	15	-
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 8 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$	-	25	40	
Fall Time	t <sub>f</sub>		-	10	15	
Drain-Source Body Diode Characteristi	cs		•		1	
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C	-	-	19	<b>.</b>
Pulse Diode Forward Current	I <sub>SM</sub>	-	-	-	40	A
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 8 A, V <sub>GS</sub> = 0 V	-	0.81	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	20	30	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	15	25	nC
Reverse Recovery Fall Time	ta	I <sub>F</sub> = 8 A, dl/dt = 100 A/μs, T <sub>J</sub> = 25 °C	-	12.5	-	ns
Reverse Recovery Rise Time	t <sub>a</sub>		_	7.5	_	

Notes

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %

b. Guaranteed by design, not subject to production testing.

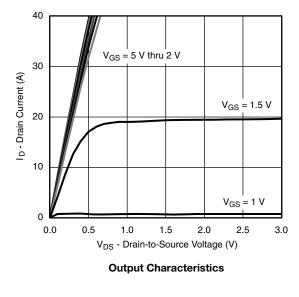
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

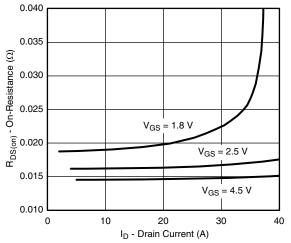
emi

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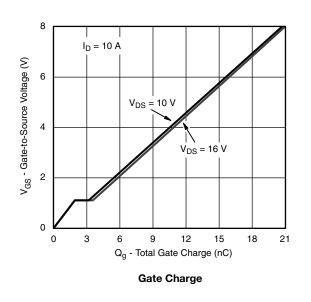


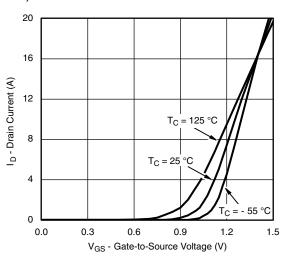




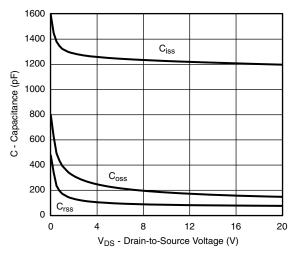


**On-Resistance vs. Drain Current and Gate Voltage** 

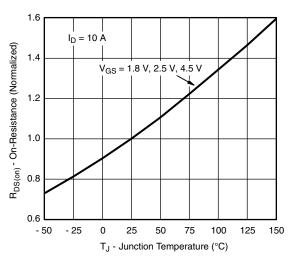




**Transfer Characteristics** 





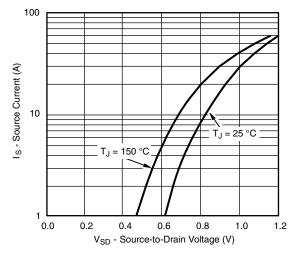


**On-Resistance vs. Junction Temperature** 

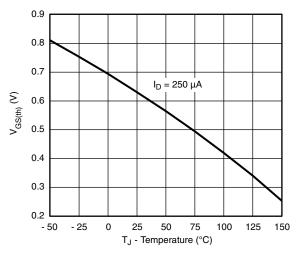
## AON3816-VB



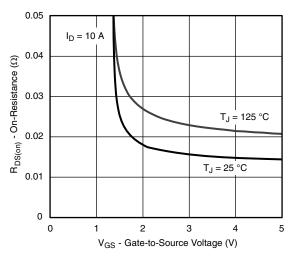
#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



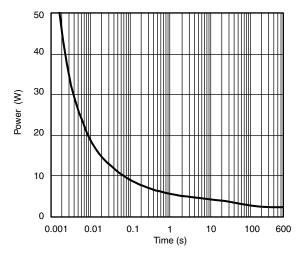
Source-Drain Diode Forward Voltage



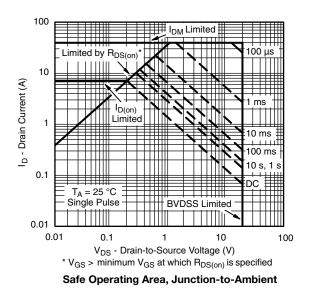
**Threshold Voltage** 



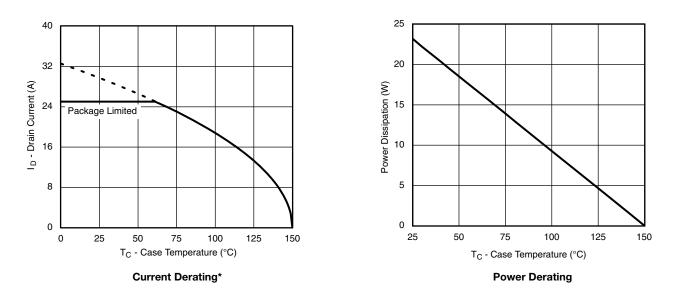
**On-Resistance vs. Gate-to-Source Voltage** 



Single Pulse Power, Junction-to-Ambient





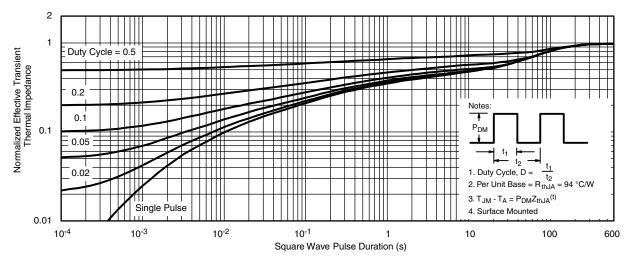


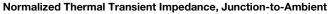
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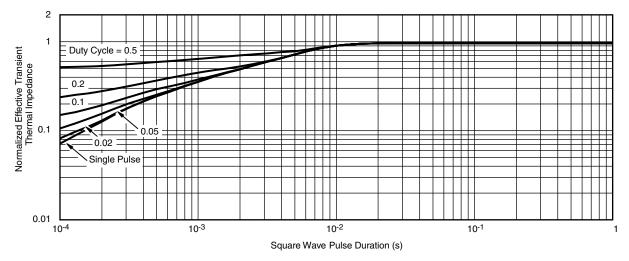
\* The power dissipation  $P_D$  is based on  $T_J$  (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



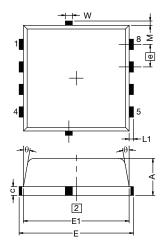


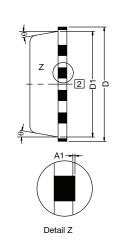


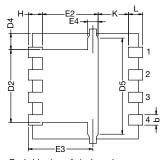
Normalized Thermal Transient Impedance, Junction-to-Case



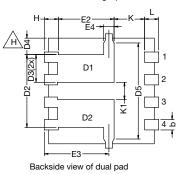
## DFN3.3X3.3 (Dual)







Backside view of single pad



 Notes

 1. Inch will govern

 2] Dimensions exclusive of mold gate burrs

 3. Dimensions exclusive of mold flash and cutting burrs

DIM.	MILLIMETERS			INCHES				
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.		
А	0.97	1.04	1.12	0.038	0.041	0.044		
A1	0.00	-	0.05	0.000	-	0.002		
b	0.23	0.30	0.41	0.009	0.012	0.016		
С	0.23	0.28	0.33	0.009	0.011	0.013		
D	3.20	3.30	3.40	0.126	0.130	0.134		
D1	2.95	3.05	3.15	0.116	0.120	0.124		
D2	1.98	2.11	2.24	0.078	0.083	0.088		
D3	0.48	-	0.89	0.019	-	0.035		
D4		0.47 typ.			0.0185 typ			
D5		2.3 typ.			0.090 typ			
E	3.20	3.30	3.40	0.126	0.130	0.134		
E1	2.95	3.05	3.15	0.116	0.120	0.124		
E2	1.47	1.60	1.73	0.058	0.063	0.068		
E3	1.75	1.85	1.98	0.069	0.073	0.078		
E4		0.034 typ.			0.013 typ.			
е	0.65 BSC			0.026 BSC				
К		0.86 typ.		0.034 typ.				
K1	0.35	-	-	0.014	-	-		
Н	0.30	0.41	0.51	0.012	0.016	0.020		
L	0.30	0.43	0.56	0.012	0.017	0.022		
L1	0.06	0.13	0.20	0.002	0.005	0.008		
θ	0°	-	12°	0°	-	12°		
W	0.15	0.25	0.36	0.006	0.010	0.014		
М	0.125 typ.			0.005 typ.				
N: S16-2667-R G: 5882	ev. M, 09-Jan-17			·				



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